


Search Notes 	Application/Control No. 10766208	Applicant(s)/Patent Under Reexamination FURUKAWA ET AL.
	Examiner Le Nguyen	Art Unit 2174

SEARCHED			
Class	Subclass	Date	Examiner
715	745	11/19/07	lvn

SEARCH NOTES		
Search Notes	Date	Examiner
EPO, JPO, ACM library, IEEE Xplore.	11/19/07	lvn
US-PGPub, USPAT: 715/745,748,742; 705/400-411,64; 709/206.	11/19/07	lvn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	745	11/19/07	lvn